Cascade Impedance Standard Substrate Map

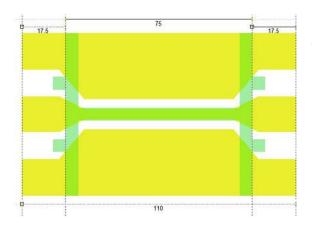
> Multiline TRL Calibration

Pitch: 25 μ m, Frequency: WR-1.0 – WR-5.1, Configuration: Ground-Signal-Ground P/N: 172-885

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Calibration Sites: 12 Site Spacing: 6000 μm x 2650 μm

	Conductor Length	Tip-to-Tip Length		
Lines	[um]	[um]		
THRU	110	75		
LINE1	120	85		
LINE2	165	130		
LINE3	220	185		
LINE4	360	325		
LINE5	460	425		
LINE6	585	550		
LINE7	710	675		
LINE8	835	800		
LINE9	935	900		
LINE10	1110	1075		

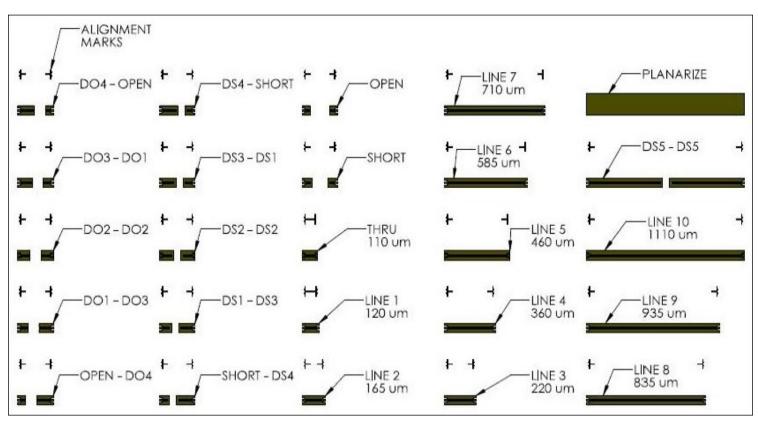


Overlay of Alignment Mark and THRU standard, showing the conductor edge-to-edge length (110 μ m) and Tip-to-Tip length (75 μ m)



> Key to Map

West Probe Fixed Index Step: 1000 μm x 500 μm , Alignment Mark Offset: 250 μm Step North



Note: Line lengths are specified as conductor edge-to-edge dimension.

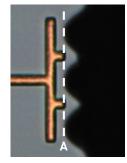
SPECIFICATIONS

Substrate Material: High-resistivity Silicon, Substrate Thickness: 275 μm Dielectric Constant: 11.8, Nominal Line Z_0: 50 Ohm

OVERTRAVEL AND ALIGNMENT

Prior to contacting the calibration standards, alignment and overtravel should be set using the alignment marks. On initial contact, the leading edge of the probe contacts should be aligned with the outmost edge "A" of the alignment mark, shown in Figure 1. To reach final contact, overtravel should be increased until the leading edge of the probe contacts is aligned with the innermost edge "B" of the alignment mark, shown in Figure 2.

Note: Calibration substrate must be mounted on an absorber material (such as ISS Holder P/N 116-344).



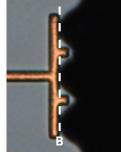


Figure 1: Initial contact

Figure 2: Final contact

> Recommended Line Configurations

Band	WR-1.0 (750 - 1100 GHz)	WR-2.2 (325 - 500 GHz)	WR-3.4 (220 - 330 GHz)	WR-4.3 (170 - 260 GHz)	WR-5.1 (140 - 220 GHz)
Lines	Thru	Thru	Thru	Thru	Thru
	Line 1	Line 2	Line 3	Line 3	Line 3
	Line 2	Line 4	Line 5	Line 6	Line 7

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